# MN74HC74/MN74HC74S

# Dual D-Type Flip-Flop with Preset and Clear

### Outline

The MN74HC74/MN74HC74S consists of D-type flip-flop with preset inputs and clear inputs, and has two built-in circuits in one chip.

The respective flip-flop has independent data input, preset input, clear input, clock input, and complementary outputs Q and  $\overline{Q}$ . Each input data is transmitted to the output at the rise of the clock pulse. The preset input and the clear input are independent of the clock input, and their active level is "L".

Owing to the silicon gate CMOS process, these flip-flops have realized low power consumption and high noise immunity equivalent to those of a standard CMOS and the operation speed as high as of an LS TTL. The outputs of the respective flip-flop can directly drive ten LS TTL inputs.

To protect the input and output against electrostatic breakdown, a resistor and a diode are used for the  $V_{\rm CC}$  and the GND. The pin configuration and the function are the same as those of the standard 54LS/74LS logic family.

## ■ Truth Table

	Inpi		Outp	ut	
PR	CLR CLK		D	Q	₽ <<
L	Н	×	×	Н	L
Н	L	×	×	L	Н
L	L	×	×	Н*	H*
Н	Н	£	Н	Н	L
Н	Н	5	L	O L	Н
Н	Н	L	×	Qo	$\overline{\overline{\mathbf{Q}}}_{0}$

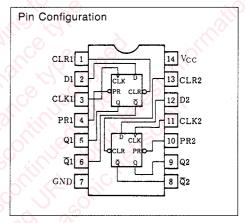
Note) 1. × : "H" or "L" either will do.

2. F: Leading in positive direction

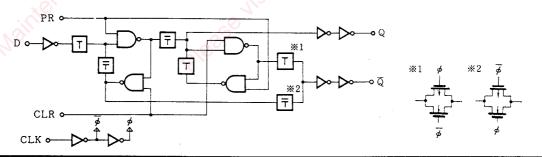
Q0: Q level before input conditions in table are confirmed.
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5. H\*: When preset, clear are "L", Q Q are H but when preset, clear are "H" simultaneously, state of Q, Q can not be predicted.

# P-1 14-pin plastic DIL package P-2 14-pin PANAFLAT package (SO-14D)



# ■ Logic Diagram



■ Absolute Maximum Ratings

Item			Symbol	Rating	Unit	
Supply voltage			$V_{cc}$	-0.5~+7.0	V	
Input output	voltage		$V_{l}, V_{O}$	$-0.5 \sim V_{cc} + 0.5$	V	
Input protect	tive diode current		$I_{IK}$	±20	mA	
Output parasitic diode current		$I_{OK}$	±20	mA		
Output current			$I_{\rm o}$	±25	mA	
Supply current			$I_{CC}$ , $I_{GND}$	±50	mA	
Storage temp	Storage temperature		$T_{ m stg}$	-65~+150	°C	
	MN74HC74	$Ta = -40 \sim +60^{\circ}C$	$P_{D}$	400	337	
Power	MIN74FIC74	$Ta = +60 \sim +85^{\circ}C$	rp	Decrease to 200mW at the rate of 8mW/°C	mW	
	MN74HC74S	Ta=-40~+60°C	$P_{D}$	275	517	
	WIN /4HC /45	$Ta = +60 \sim +85^{\circ}C$	I D	Decrease to 200mW at the rate of 3.8mW/°C	mW	

■ Recommended Operating Conditions

Item	Symbol	V <sub>cc</sub> (V)	Rating	Unit V	
Operating power supply voltage	Vcc		1.4~6.0		
Input output voltage	V <sub>I</sub> , V <sub>O</sub>		0~Vcc	V	
Operating temperature	$T_A$		-40~+85	°C	
		2.0	0~1000	ns	
Input rise, fall time	t <sub>r</sub> , t <sub>f</sub>	4.5	0~500	ns	
		6.0	0~400	ns	

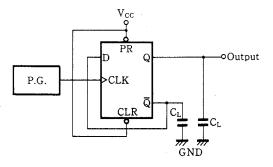
■ DC Characteristics (GND=0V)

Item		V <sub>cc</sub> (V)	Test Condition			Temperature					
	Symbol		Vį	V		Ta=25°C			Ta=-40~+85°C		Unit
				$V_{I}$ $V_{O}$	Unit	min.	typ.	max.	min.	max.	
		2.0				1.5			1.5		
Input voltage high level	$V_{IH}$	4.5				3.15			3.15		V
		6.0				4.2			4.2		
		2.0						0.3		0.3	
Input voltage low level	$V_{IL}$	4.5						0.9		0.9	V
		6.0						1.2		1.2	
		2.0		-20.0	μA	1.9	2.0		1.9		
		4.5	V <sub>IH</sub>	-20.0	$\mu$ A	4,4	4.5		4.4		
Output voltage high level	V <sub>OH</sub>	6.0	or	-20.0	$\mu$ A	5.9	6.0	:	5.9		V
		4.5	V <sub>IL</sub>	-4.0	mA	3.92			3.84		
		6.0		-5.2	mA	5.48			5.34		
		2.0		20.0	$\mu$ A		0.0	0.1		0.1	
		4.5	$V_{IH}$	20.0	μA		0.0	0.1		0.1	
Output voltage low level	V <sub>OL</sub>	6.0	or	20.0	μA		0.0	0.1		0.1	V
		4.5	V <sub>IL</sub>	4.0	mA			0.26		0.33	
		6.0		5.2	mA			0.26		0.33	
Input leakage current	I <sub>I</sub>	6.0	$V_I = V_{CC}$	or GNI	)			±0.1		±1.0	μΑ
Static supply current	Icc	6.0	$V_{I} = V_{CC}$	or GNI	$I_0=0$			4.0		40.0	μΑ

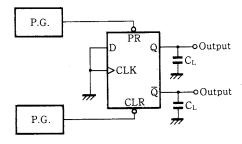
■ AC Characteristics (GND=0V, Input transition time ≤6ns, C<sub>L</sub>=50pF)

		V <sub>cc</sub> (V)	Test Condition	Temperature					
Item	Symbol			Ta=25°C			$Ta = -40 \sim +85^{\circ}C$		Unit
				min.	typ.	max.	min.	max.	
		2.0			25	75		95	
Output rise time	t <sub>TLH</sub>	4.5			8	15		19	ns
		6.0			7	13		16	
		2.0			20	75		95	
Output fall time	tTHL	4.5			7	15		19	ns
		6.0			6	13		16	
		2.0			32	150		190	
Propagation time	t <sub>PLH</sub>	4.5			14	30	:	38	ns
$CLK \rightarrow Q, \overline{Q} (L \rightarrow H)$		6.0			11	26		33	
		2.0			32	150		190	
Propagation time	t <sub>PHL</sub>	4.5			14	30		38	ns
$CLK \rightarrow Q, \overline{Q} (H \rightarrow L)$		6.0			11	26		33	
		2.0			32	150		190	
Propagation time	t <sub>PLH</sub>	4.5			14	30		38	ns
PR, CLR $\rightarrow$ Q, $\overline{Q}$ (L $\rightarrow$ H)	1 1311	6.0			10	26		33	
	1	2.0	,		32	150		190	
Propagation time	t <sub>PHL</sub>	4.5			13	30		38	ns
PR, CLR $\rightarrow$ Q, $\overline{Q}$ (H $\rightarrow$ L)		6.0			10	26		33	
		2.0		-	7	75		95	
Minimum set-up time	t <sub>su</sub>	4.5			4	15		19	ns
minimizer oct up time	-su	6.0			3	13		16	
		2.0			<del>  _</del>	0		0	
Minimum hold time	t <sub>h</sub>	4.5				0		0	ns
William Hold three	Ųn.	6.0				0		0	110
		2.0			26	75		95	<del></del>
Minimum pulse width	t <sub>w</sub>	4.5			9	15		19	ns
PR, CLR	LW.	6.0			7	13		16	110
Minimum recovery time		2.0		+	5	75		95	
	t <sub>rem</sub>	4.5			4	15		19	ns
PR, CLR		6.0			2	13		16	113
	-	2.0		6	20	13	4	10	
Maximum clock frequency		4.5		30	58		24		MHz
махинин сюск пеquency	f <sub>max</sub>	i		35	70	1	28		141117
		6.0		35	70	1	20		

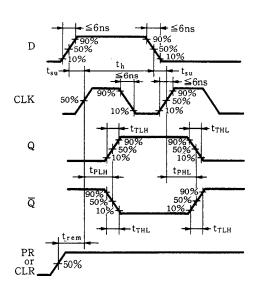
- · Switching time measuring circuit and waveforms
  - (1)  $t_{TLH}$ ,  $t_{THL}$ ,  $t_{su}$ ,  $f_{max}$ ,  $t_{PLH}/t_{PHL}$  (CLK $\rightarrow$ Q,  $\overline{Q}$ ),  $t_{rem}$ ,  $t_h$
  - 1. Measuring circuit



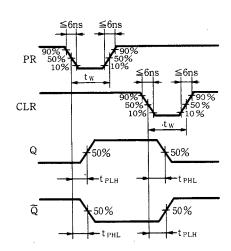
- (2)  $t_{PLH}/t_{PHL}$  (PR, CLR $\rightarrow$ Q  $\overline{Q}$ ),  $t_w$  (PR, CLR)
- 1. Measuring circuit



## 2. Switching waveforms



## 2. Switching waveforms



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